



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:
Sun, et al.

Serial No.: 10/611,805

Confirmation No.: Unknown

Filed: June 30, 2003

For: An Effective Method to
Improve Surface Finish in
Electrochemically Assisted
CMP

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Group Art Unit: Unknown

Examiner: Unknown

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE OF MAILING 37 CFR 1.8	
I hereby certify that this correspondence is being deposited on <u>11/06</u> , 2003 with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450.	
<u>11/06/2003</u> Date	<u>[Signature]</u> Signature

Dear Sir:

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The Applicants, and the Attorney who signs below on the basis of the information supplied by the inventor and the information in his file, submit herewith patents, publications, or other information of which they are aware, which may be material to the examination of this application and in respect of which there may be a duty to disclose in accordance with 37 CFR § 1.56.


While the information submitted in this Information Disclosure Statement may be material pursuant to 37 CFR § 1.56, it is not intended to constitute an admission that any patent, publication, or other information referred to therein is prior art for this invention unless specifically designated as such.

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The patents and/or publications submitted herewith are set forth on the attached Form PTO-1449.

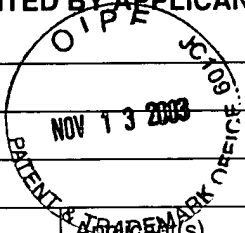
If the sum of \$180.00 is due under 37 CFR § 1.17(p) pursuant to § 1.97, the Commissioner is hereby authorized to charge this fee, and any other fee necessary to make this submission timely, to the Deposit Account No. 20-0782/AMAT/6877/BKH.

Respectfully submitted,



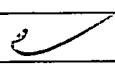
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U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)					Docket No. APPM/6877/CMP/ CMP/RKK		Serial No. 10/611,805	
LISTS OF PATENTS AND PUBLICATIONS CITED BY APPLICANT (Use several sheets if necessary)					Applicant Sun, et al.		Confirmation No. UNKNOWN	
Examiner UNKNOWN					Filing Date June 30, 2003		Group UNKNOWN	



U.S. Patent Documents							
*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
	A28	6,066,030	05/23/2000	Uzoh	451	41	03/04/1999
	A29	6,056,851	05/02/2000	Hsieh, et al.	156	345	08/14/1998
	A30	6,024,630	02/15/2000	Shendon, et al.	451	41	06/09/1995
	A31	6,020,264	02/01/2000	Lustig, et al.	438	692	01/31/1997
	A32	6,017,265	01/25/2000	Cook et al.	451	41	01/13/1997
	A33	6,004,880	12/21/1999	Liu, et al	438	692	02/20/1998
	A34	6,001,008	12/14/1999	Fujimori, et al.	451	443	04/15/1999
	A35	5,938,801	08/17/1999	Robinson	51	306	08/20/1998
	A36	5,911,619	06/15/1999	Uzoh, et al	451	5	03/26/1997
	A37	5,871,392	02/16/1999	Meikle et al.	451	56	06/13/1996
	A38	5,846,882	12/08/1998	Birang	438	692	10/03/1996
	A39	5,807,165	09/15/1998	Uzoh, et al	451	41	03/26/1997
	A40	5,804,507	09/08/1998	Perlov, et al.	438	692	10/27/1995

F reign Patent Documents								
*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
	B12	WO 99/53119	10-21-1999	WIPO	C23C	18/18		X
	B13	WO 99/41434	08-19-1999	WIPO	C25D	5/02		X
	B14	WO 98/49723	11/05/1998	WIPO	H01L	21/321		X

OTHER ART		
*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.
	C5	International Search Report for PCT/US 02/11009 dated February 6, 2003. 
	C6	
	C7	
	C8	

Examiner	Date Considered
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Examiner UNKNOWN					Filing Date June 30, 2003		Group UNKNOWN	

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U.S. Patent Documents							
*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
	A41	5,738,574	04/14/1998	Tolles, et al.	451	288	10/27/1995
	A42	5,624,300	04/29/1997	Kishii, et al.	451	36	07/10/1996
	A43	5,578,362	11/26/1996	Reinhardt et al.	428	147	07/12/1994
	A44	5,575,706	11/19/1996	Tsai, et al	451	41	01/11/1996
	A45	5,567,300	10/22/1996	Datta, et al	205	652	09/02/1994
	A46	5,543,032	08/06/1996	Datta, et al	205	670	06/02/1995
	A47	5,136,817	08/11/1992	Tabata, et al.	51	165.71	02/28/1991
	A48	4,956,056	09/11/1990	Zubatova, et al	204	129.43	03/20/1989
	A49	4,954,141	09/04/1990	Takiyama et al.	51	296	01/25/1989
	A50	4,839,993	06/20/1989	Masuko, et al.	51	129	01/16/1987
	A51	4,793,895	12/27/1988	Kaanta, et al.	156	627	01/25/1988
	A52	4,125,444	11/14/1978	Inoue	204	129.43	12/13/1977
	A53	3,873,512	03/25/1975	Latanision	204	129.46	04/30/1973
	A54	3,162,588	12/22/1964	Bell	204	141	04/17/1961
	A55	2003/0114087	06/19/2003	Duboust, et al.	451	41	06/04/2002
	A56	2003/0116445	06/26/2003	Sun, et al.	205	674	05/07/2002
	A57	2002/0130049	09/19/2002	Chen, et al.	205	640	01/03/2002
	A58	2002/0119286	08/29/2002	Chen, et al.	428	131	12/27/2001
	A59	2003/0116446	06/26/2003	Duboust, et al.	205	682	12/21/2001

Foreign Patent Documents								
*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
	B15	0 455 455	04/29/1991	EP	B23Q	15/007		X

OTHER ART	
*Examiner Initial	Including Author, Title, Date, Pertinent Pages, Etc.
	C9

Examiner	Date Considered
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U.S. Patent Documents							
*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
	A13	6,297,159	10/02/2001	Paton	438	693	07/07/1999
	A14	6,273,798	08/14/2001	Berman	451	72	07/27/1999
	A15	6,248,222	06/19/2001	Wang	204	297.09	09/07/1999
	A16	6,244,935	06/12/2001	Birang, et al.	451	41	02/04/1999
	A17	6,238,271	05/29/2001	Cesna	451	41	04/30/1999
	A18	6,234,870	05/22/2001	Uzoh, et al	451	8	08/24/1999
	A19	6,210,257	04/03/2001	Carlson	451	56	05/29/1998
	A20	6,176,992	01/23/2001	Talieh	205	87	12/01/1998
	A21	6,171,467	01/09/2001	Weihs et al.	205	93	11/24/1998
	A22	6,159,079	12/12/2000	Zuniga, et al.	451	41	09/08/1998
	A23	6,156,124	12/05/2000	Tobin	118	719	10/06/1999
	A24	6,153,043	11/28/2000	Edelstein, et al.	156	345	02-06-1998
	A25	6,116,998	09/12/2000	Damgaard, et al.	451	490	01/13/1998
	A26	6,103,096	08/15/2000	Datta, et al	205	686	11/12/1997
	A27	6,090,239	07/18/2000	Liu. et al	156	345	08/02/1999

Foreign Patent Documents								
*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
e	B7	WO 01/49452	07-12-2001	WIPO	B24B	37/04		X
e	B8	WO 00/59682	10-12-2000	WIPO	B24B	37/04		X
e	B9	WO 00/33356	06-08-2000	WIPO	H01L	---		X
e	B10	WO 00/26443	05-11-2000	WIPO	C25D	---		X
e	B11	WO 00/03426	01-20-2000	WIPO	H01L	21/321		X

OTHER ART		
*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.
	C2	U.S. Patent Application 10/151,538 filed on May 16, 2002.
Examiner		Date Considered

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Examiner UNKNOWN		Filing Date June 30, 2003	Group UNKNOWN

U.S. Patent Documents

*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
	A1	2002/0077037	06/20/2002	Tietz	451	41	07/20/2001
	A2	2002/0070126	06/13/2002	Sato	205	640	09/19/2001
	A3	2002/0008036	01/24/2002	Wang	205	118	04/18/2001
	A4	2001/0042690	11/22/2001	Talieh	205	118	12/14/2000
	A5	2001/0040100	11/15/2001	Wang	205	220	04/16/2001
	A6	2001/0036746	11/01/2001	Sato et al.	438	745	03/08/2001
	A7	2001/0024878	09/27/2001	Nakamura	438	691	03/26/2001
	A8	6,440,295	08/27/2002	Wang	205	640	02/04/2000
	A9	6,395,152	05/28/2002	Wang	204	224 M	07/02/1999
	A10	6,391,166	05/21/2002	Wang	204	224 R	01/15/1999
	A11	6,386,956	05/14/2002	Sato, et al.	451	57	11/01/1999
	A12	6,381,169	04/30/2002	Bocian, et al.	365	151	07/01/1999

Foreign Patent Documents

*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
	B1	EP 0 325 753	08-02-1989	EP	H01L	21/00		X
	B2	2001-77117	03-23-2001	JAPAN	H 01 L	21/3205		X
	B3	JP 11042554	02-16-1999	JAPAN	B24B	37/04		X
	B4	WO 02/23616	03-21-2002	WIPO	H01L	21/44		X
	B5	WO 02/064314	08-22-2002	WIPO	B24B	37/04		X
	B6	WO 01/88229	11-22-2001	WIPO	C25F	3/30		X

OTHER ART

*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.
	C1	Nogami, "An Innovation in Integrate Porous Low-K Materials and Copper," <u>InterConnect Japan 2001</u> ; Honeywell Seminar December 6, 2001, p 1-12.

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